Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10769786	CHOI ET AL.
Examiner	Art Unit
Nguyen, Jennifer T	2629

SEARCHED							
Class	Subclass	Date	Examiner				
345	60-72,88-104	3/17/07	, JN				

SEARC	H NOTES	
Search Notes	Date	Examiner
east, iEEE, JPO	3/17/07	JN

INTERFERENCE SEARCH							
Class		Subclass	Date	Examiner			
315	169.1,169.4		3/17/07	JN			